Open Microphone –
Wanted: New Test Directions & Practical Test Bottlenecks

Fidel Muradali – Agilent Technologies

In this session, the audience is asked to help identify the top 10 hot test topics for the next 5 years. It is time to re-align test technology R&D to target the new gaps and problems faced by industry. There is a wide range of nagging issues. For example, what is DFT for RF products? What is low-cost verification? What really are the defect mechanisms for .1um and lower? What are the new board-test issues? Will IDDQ work next year? How can manufacturing-test be optimized? The list can seem never ending.

ITC provides unique forum for industrial customers, suppliers and academia to communicate. In order to truly advance test, the first step is to recognize mature subjects and identify future needs or, more importantly, the big win directions. Here at ITC, all the players are present so we provide the opportunity to do this.

Organizer: Fidel Muradali – Agilent Technologies

Moderator: Phil Nigh - IBM